Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination CHRISTIAN ET AL.	
10/086,807		
Examiner	Art Unit	
Julian Mercado	1745	

SEARCHED				
Class	Subclass	Date	Examiner	
<u> </u>				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES				
(INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST search (a tailed)	1/9/96	OM		
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